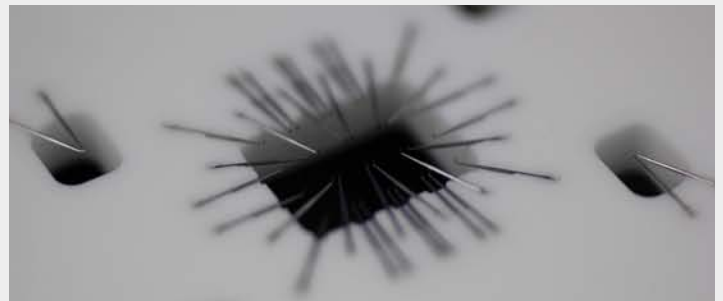
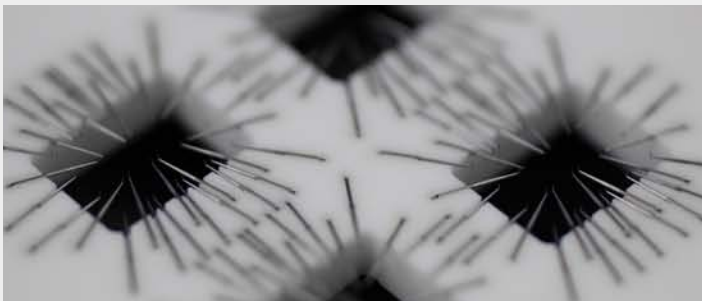


T90™ SERIES PROBE CARDS

CELADON™

4.5" WAFER LEVEL RELIABILITY PROBE CARD



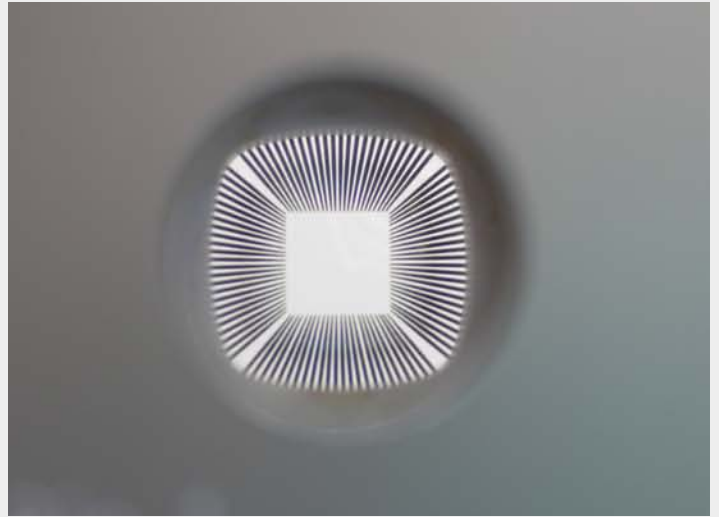
T90 ceramic probe cards are optimized for small area multi-site wafer level reliability testing. The card is compatible with standard 4.5" probe card holders and can deliver consistently accurate results in a small rack or stack test matrices and probers.

The T90 probe card has the same low expansion properties, crash resistant design, and ultra high performance as Celadon's other ceramic probe cards, and is a rugged, dependable, and accurate component for any wafer level reliability test system.

Low Leakage at 10 seconds:

- Leakage < 5fA/V from -65° to 125°C
- Leakage < 20 fA/V from 125° to 200°C
- Leakage < pA/V from 200° to 300°C

- Standard operating range -65° to 300°C, optional to 400°C
- Up to 250 probes per Low Leakage card
- Up to 500 probes per High Temperature card
- Fits standard 4.5" probe card holders
- Minimum pitch pattern-dependent
- Standard X-Y accuracy 10% pad size
- Standard Z accuracy +/- 5 microns per site
- Size: 160 x 114 x (15-25) mm; .5 kg



T90™ SERIES PROBE CARDS